

P603-1 / P750 set

RF Conducted Measurement IEC 61967-4, 1 Ohm / 150 Ohm

LANGER
EMV-Technik



Short description

The probe set is used to measure conducted emissions (measurements with direct 1 Ohm/150 Ohm-coupling) according to IEC 61967-4 at IC pins. For the current and voltage measurement there is one respective probe available. Every Test-IC pin can be reached and contacted by the probe.

The measurements with the probe set guarantee a high precision when repeated and comparability of measurements. The ICE1 IC test environment of Langer EMV-Technik is used to start the test IC. measurements can be done with ChipScan-ESA software. Measurement results of all measured pins are saved in the software and can be compared fast and systematically.

Scope of delivery

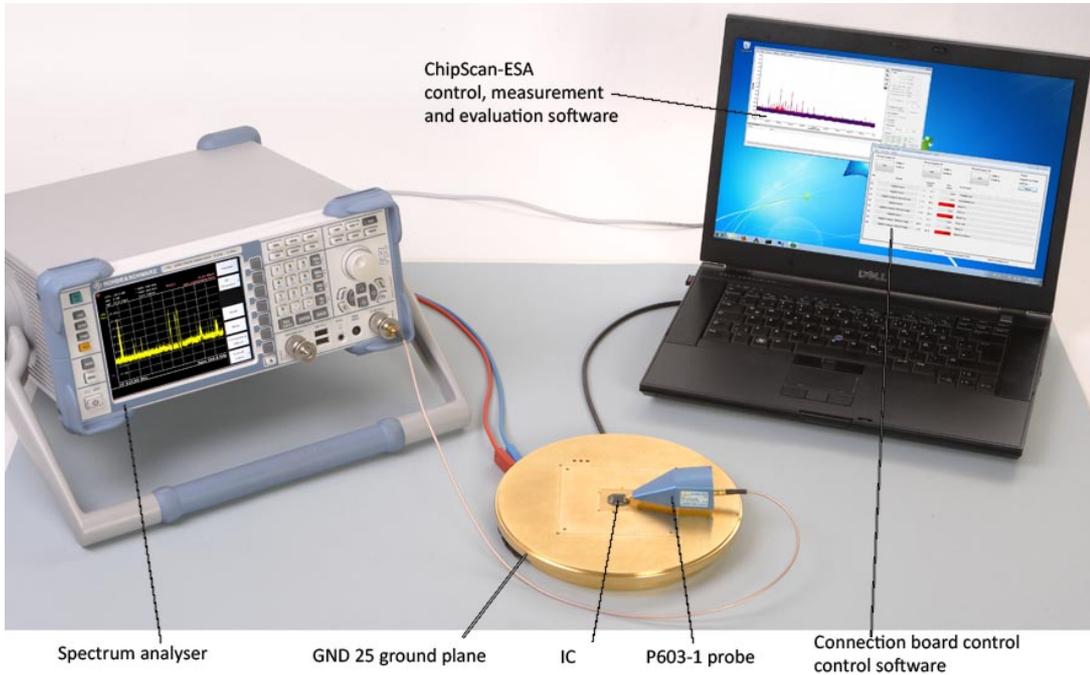
- 1x P603-1, RF Current Probe 1 Ohm
- 1x P750, RF Voltage Probe 150 Ohm
- 1x CS-ESA, ChipScan-ESA Software / USB
- 1x SMA-SMB 1 m, SMA-SMB Measuring Cable
- 1x NT FRI EU, Power Supply Unit
- 1x P603 / P750 case, System Case
- 1x P603-1 / P750 m, P603 / P750 Set User Manual

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Application with P603-1



Scheme measurement set-up with P750

